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Application/Control No.	Applicant(s)/Patent Under Reexamination
	SONI ET AL

2611

Art Unit Examiner

SEARCHED						
Class	Subclass	Date	Examiner			
375	355	2/15/2007	LF			
370	206, 338	2/15/2007	LF			

Flores, Leon

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted with SPE David Payne in regards to the patentability of claim 1	2/20/2007	LF		
Search in NPL (IEEE)	2/15/2007	LF		
Checked for possible Double Patenting.	2/15/2007	LF		
Consulted with SPE David Payne in regards to the amendments.	9/7/2007	LF		
Consulted with SPE David Payne in regards to the amendments.	12/11/2007	LF		
Consulted with SPE Shuwang Liu in regards to the RCE.	2/8/2008	LF		
Consulted with SPE David Payne in regards to the RCE.	2/21/2008	LF		

	INTERFERENCE SEA	RCH	
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